nSpec Version 0.22.1.3

Release Date: 03 Feb 2023

Documentation Updated: 01 Feb 2023

Major Features:

Overview

This release patch fixes some key issues with nSpec’s automatic calibration utility, and Gen4 AI Analysis when run on Device Scans. This version also implements a new feature for the Custom Exporter post-analysis, which can now export customizable KLARF files.

Upgrading to v0.22.1.3

✓ Library Update Not Required

If upgrading from a version more than 1 release prior, please reference all intermediate release notes for upgrade steps *for each version*.

New Features

Highlights

NSPEC-5407: Custom Exporter - Customizable KLARF outputs

KLARF file exports are now supported as part of the universal `Custom Exporter` following any nSpec Analysis. Defects identified will be reported as part of the `DefectList` field within the KLARF file, with customizable columns reported based on customer-specific requirements. Column data can be defined as part of the Custom Exporter SQL query.

> *For assistance setting up a Custom Exporter SQL query for a customer integration, please contact the Nanotronics application engineering team at appengineering@nanotronics.co*

New Features Changelog

T	Key	Release Notes Summary
	NSPEC-5407	Custom Exporter - Customizable KLARF outputs
	NSPEC-6784	Add DefectRecordSpec DefectList in Custom KLARF export

2 issues

Bug Fixes

Highlights

NSPEC-6168: Calibration utility moves stage inappropriately for objective resolution calibrations

For the last several releases, the calibration utility could not perform the `Calibrate XY Objective Resolutions` calibration successfully without manual intervention because the stage drove to incorrect places on the Nanotronics calibration wafer. This caused some headache for initial setup of new nSpec systems, but also for preventative maintenance to monitor stage accuracy is maintained across the lifetime of nSpec systems that have already been actively deployed. This fix addresses this issue such that the latest nSpec Calibration Wafer standard can now be used for stage accuracy monitoring using the automated functionality.

NSPEC-6645: Defects in Gen4 analysis always register to last device in image

When running a Gen4 analysis on a device scan, defect’s parent device ID will always be logged as the last device in the image, instead of the device ID of the device the defect is actually on. This has now been fixed.

Changelog

T	Key	Release Notes Summary	Affected Releases
🟥	NSPEC-6186	Calibration utility moves stage inappropriately for resolution calibrations	0.22.1.0
🟥	NSPEC-6645	Defects in Gen4 analysis always register to last device in image	0.22.0.0, 0.22.1.0

2 issues